

Notice of References Cited	Application/Control No. 10/002,933	Applicant(s)/Patent Under Réexamination LEE ET AL.	
	Examiner Leigh McKane	Art Unit 1744	Page 1 of 1

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	C	US-5,849,846	12-1998	Chen et al.	525/166
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	M	US-			

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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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